

Supplementary information for

CuSCN as a hole transport layer in inorganic solution-processed planar Sb<sub>2</sub>S<sub>3</sub> solar cell: enabling carbon-based and semitransparent photovoltaics

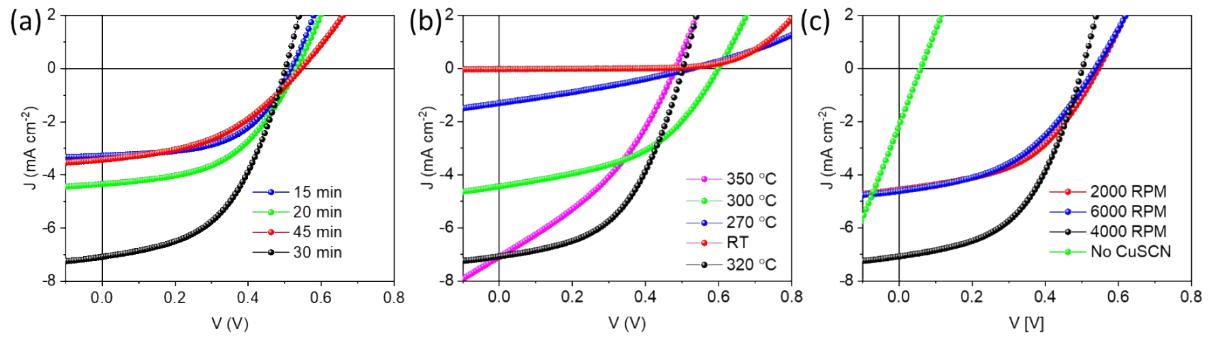
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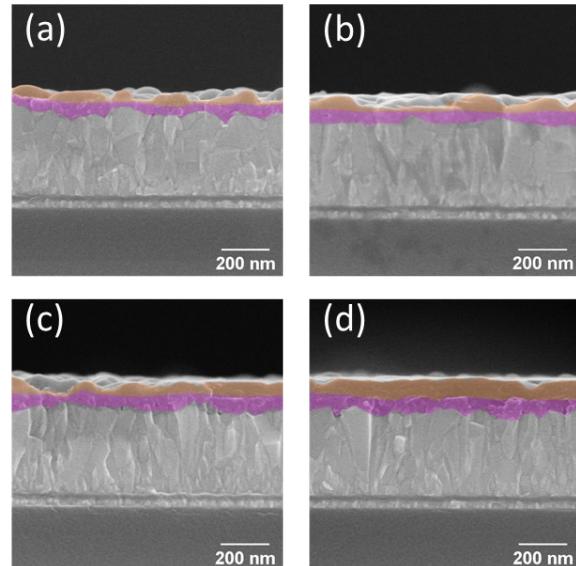


**Figure S1.** (a) The J-V curves of the best solar cells at different (a)  $\text{Sb}_2\text{S}_3$  CBD times, (b)  $\text{Sb}_2\text{S}_3$  annealing temperatures, and (c) CuSCN spin coating speeds.

**Table S1.** Photovoltaic parameters of the best solar cells with different CBD times.

CBD time [thickness] <sup>a</sup>	$J_{\text{SC}}$ [ $\text{mA cm}^{-2}$ ]	$V_{\text{OC}}$ [V]	FF [%]	PCE [%]
15 min [35 nm]	3.3	0.52	0.54	0.90
20 min [45 nm]	4.3	0.53	0.50	1.15
30 min [50 nm]	7.1	0.50	0.50	1.75
45 min [70 nm]	3.4	0.54	0.44	0.81

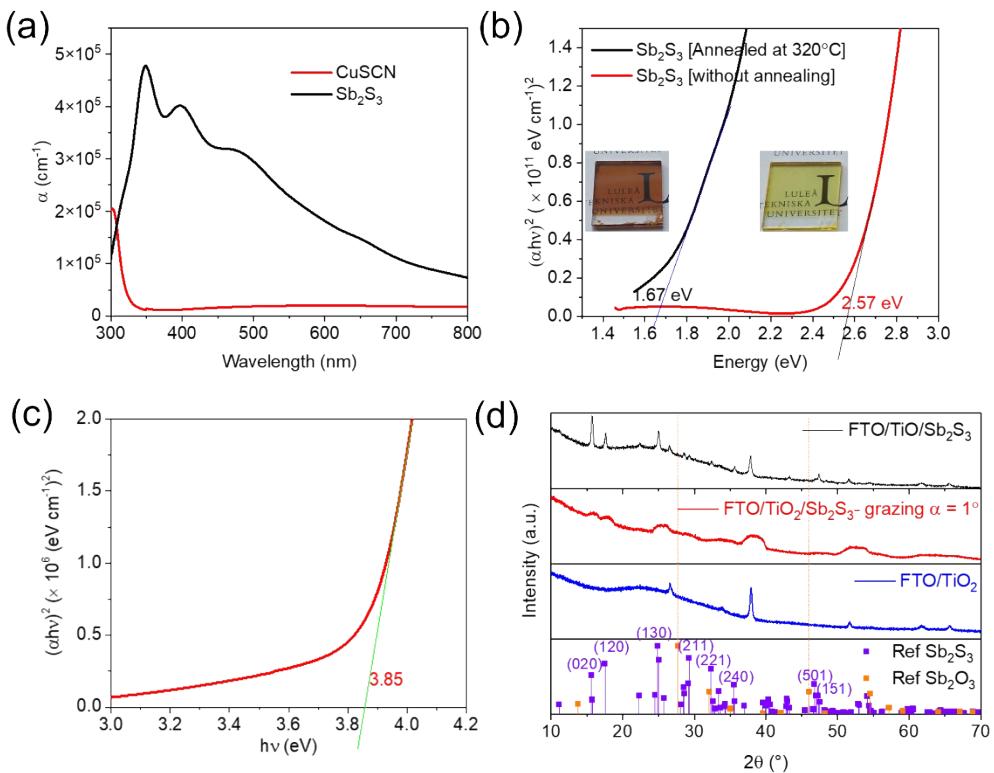
<sup>a</sup>Typical heights of the  $\text{Sb}_2\text{S}_3$  islands.



**Figure S2.** Cross-section images of FTO/TiO<sub>2</sub>/CBD-Sb<sub>2</sub>S<sub>3</sub> stack with different CBD times. (a) 15 min, (b) 20 min, (c) 30 min, and (d) 45 min. Island type growth can be clearly seen in (a) and (b).

**Table S2.** Photovoltaic parameters of the best solar cells with different annealing temperatures.

Annealing temperature	J <sub>SC</sub> [mA cm <sup>-2</sup> ]	V <sub>OC</sub> [V]	FF [%]	PCE [%]
RT	0.03	0.40	0.31	0.00
270 °C	1.3	0.53	0.29	0.20
300 °C	4.4	0.60	0.46	1.20
320 °C	7.1	0.50	0.50	1.75
350 °C	7.1	0.48	0.36	1.20



**Figure S3.** (a) Absorption spectra of CuSCN thin film on glass, Sb<sub>2</sub>S<sub>3</sub>, and Sb<sub>2</sub>S<sub>3</sub> on FTO/TiO<sub>2</sub> substrates. Tauc-plots to calculate the bandgap of (b) Sb<sub>2</sub>S<sub>3</sub> and (c) CuSCN thin films. (d) XRD spectrum of Sb<sub>2</sub>S<sub>3</sub> thin film on FTO/TiO<sub>2</sub> substrates

**Table S3.** Photovoltaic parameters of the best solar cells with different RPMs of CuSCN deposition.

Spin coating RPM [thickness] <sup>a</sup>	J <sub>SC</sub> [mA cm <sup>-2</sup> ]	V <sub>OC</sub> [V]	FF [%]	PCE [%]
2000 RPM [110 nm]	4.3	0.54	0.47	1.18
4000 RPM [70 nm]	7.1	0.50	0.50	1.75
6000 RPM [45 nm]	4.6	0.54	0.44	1.10
No CuSCN	2.6	0.05	0.23	0.03

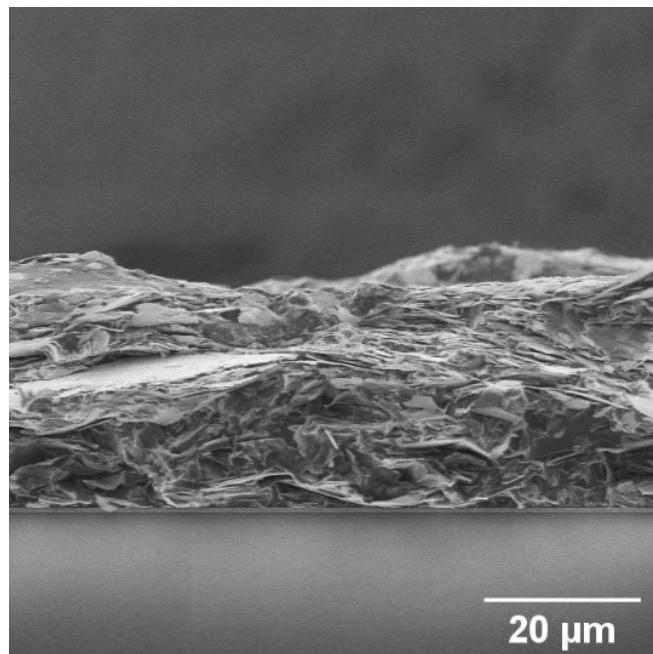
<sup>a</sup> thickness measured from cross-section SEM images of FTO/CuSCN films.**Table S4.** Electrical parameters of FTO, TiO<sub>2</sub>, Sb<sub>2</sub>S<sub>3</sub>, and CuSCN, used in SCAPS-1D simulation.

Parameters	FTO <sup>1,2</sup>	TiO <sub>2</sub> <sup>3</sup>	Sb <sub>2</sub> S <sub>3</sub> <sup>3</sup>	CuSCN
CBM (eV)	4.4	4.0	3.7	1.6 <sup>4</sup>
Bandgap (eV)	3.5	3.3	1.7	3.8
Dielectric constant	9	31	7.1 <sup>5</sup>	5.1 <sup>6</sup>
CB N <sub>eff</sub> (cm <sup>-3</sup> )	$2.2 \times 10^{18}$	$10^{19}$	$5 \times 10^{19}$	$2.2 \times 10^{187}$
VB N <sub>eff</sub> (cm <sup>-3</sup> )	$1.8 \times 10^{19}$	$10^{19}$	$10^{20}$	$1.8 \times 10^{187}$
$\mu_{\text{electron}}$ (cm <sup>2</sup> /Vs)	20	10	0.8 <sup>3</sup>	100 <sup>7</sup>
$\mu_{\text{hole}}$ (cm <sup>2</sup> /Vs)	10	1	0.2 <sup>3</sup>	25 <sup>7</sup>
Doping, N <sub>A/D</sub> (cm <sup>-3</sup> )	$10^{19}$	$10^{17}$	Intrinsic <sup>3</sup>	$1.0 \times 10^{187}$
Defect type <sup>a</sup>	-	Neutral	Neutral	
Defect density (cm <sup>-3</sup> )	-	$10^{17}$	$10^{12}$	$10^{158}$

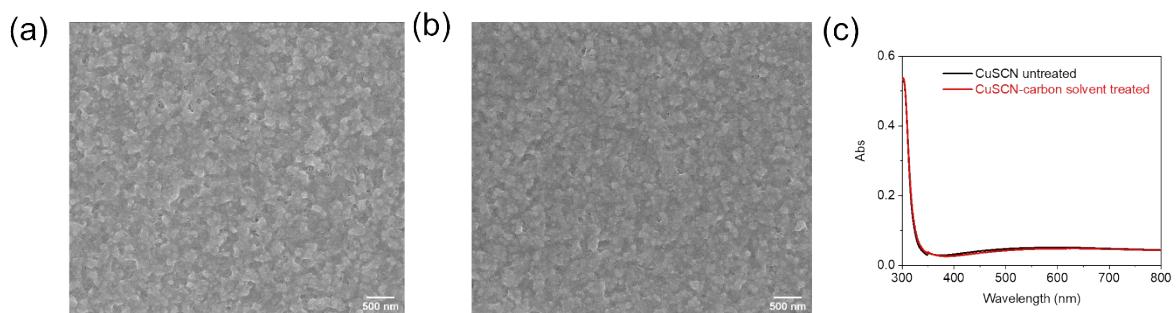
Defect capture cross-section ( $\text{cm}^{-2}$ )	-	$10^{-16} (\text{n})$	$10^{-14} (\text{n})$	$10^{-16} (\text{p})$
			$5 \times 10^{-15} (\text{p})$	
Defect energetic position (eV)	-	$E_v + 1.8$	$E_v + 0.52$	$E_v + 0.90^9$
Thickness (nm)	50	50	50	50

<sup>a</sup>All the defect-related parameters were taken from Kondrotas et al.<sup>3</sup>

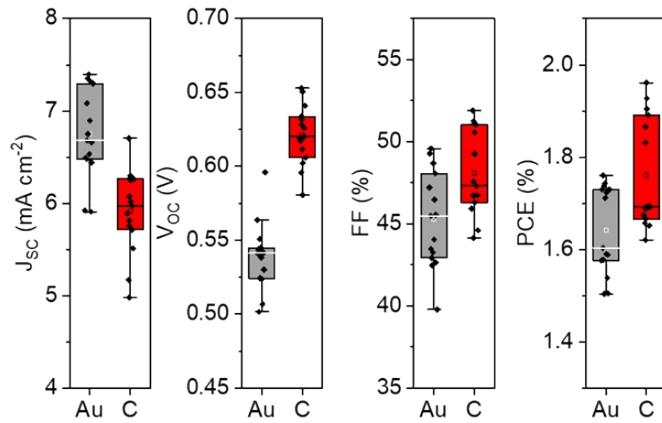
CBM: Conduction band maximum; CB/VB  $N_{\text{eff}}$ : conduction band/valence band effective density of states;  $\mu$ : mobility



**Figure S4.** A zoomed-out SEM image of the C-electrode device.



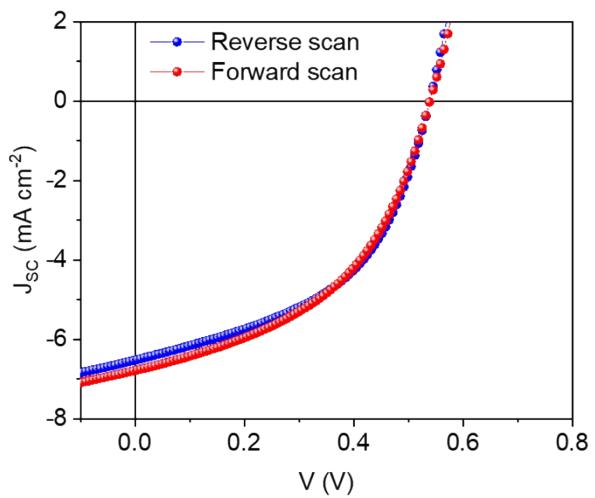
**Figure S5.** Top view SEM images of (a) FTO/TiO<sub>2</sub>/Sb<sub>2</sub>S<sub>3</sub>/CuSCN and FTO/TiO<sub>2</sub>/Sb<sub>2</sub>S<sub>3</sub>/CuSCN-carbon solvent treated films. (c) Absorption spectra of CuSCN films with and without treatment with carbon solvent.



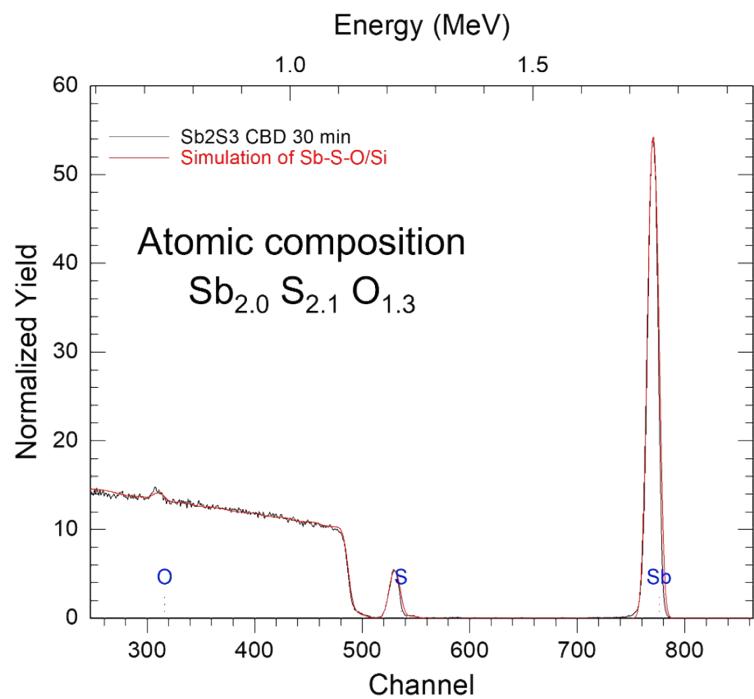
**Figure S6:** Statistical data of 15 devices fabricated using C and Au electrodes.

**Table S5.** Literature reports of planar solution processed Sb<sub>2</sub>S<sub>3</sub> solar cells with CuSCN as HTL.

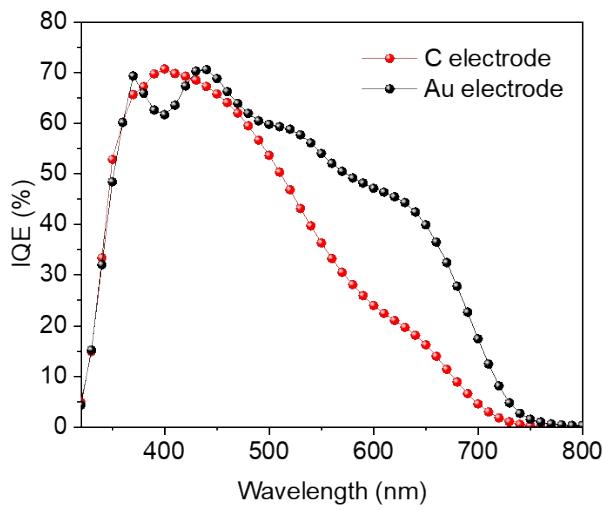
Electrode	CuSCN deposition	Sb <sub>2</sub> S <sub>3</sub> deposition	V <sub>OC</sub> [V]	J <sub>SC</sub> [mA cm <sup>-2</sup> ]	FF [%]	PCE [%]	Ref
Au	Spin coating	CBD	0.46	5.44	0.33	0.80	<sup>10</sup>
Au	Spin coating	Thermal evaporation	0.60	6.43	0.44	1.69	<sup>10</sup>
Au	Impregnation	CBD	0.48	4.85	0.38	0.90	<sup>11</sup>
Au	Impregnation	Sputtering	0.59	5.26	0.54	1.67	<sup>11</sup>
Au	Wiping	CBD	0.55	4.30	0.35	0.83	<sup>12</sup>
Au	Spin coating Carbon	CBD	0.50	7.10	0.50	1.75	This work
			0.61	6.25	0.51	1.95	



**Figure S7.** Forward vs. reverse scan of a device with Au electrode. Forward scan (-0.1 to 1 V):  $V_{OC} = 0.539$ ,  $J_{SC} = 6.8 \text{ mA cm}^2$ , FF = 0.46, PCE = 1.70 %; Reverse scan (1 to -0.1 V):  $V_{OC} = 0.538$ ,  $J_{SC} = 6.5 \text{ mA cm}^2$ , FF = 0.49, PCE = 1.70 %.



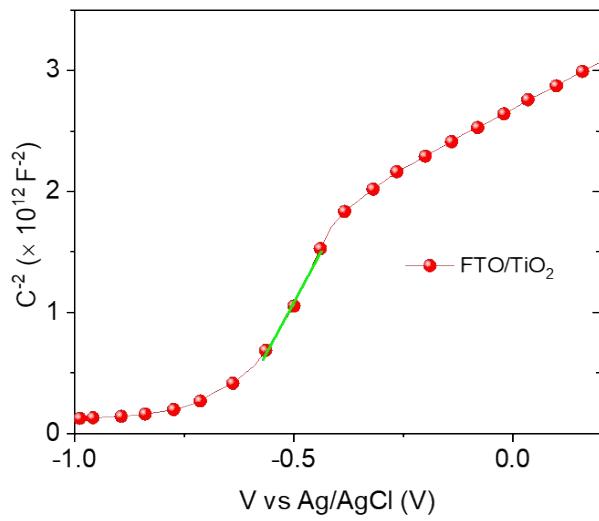
**Figure S8.** RBS spectrum of the annealed  $\text{Sb}_2\text{S}_3$  film. Black line: experiment. Red line: RUMP code simulation. The atomic composition is obtained from the simulation.



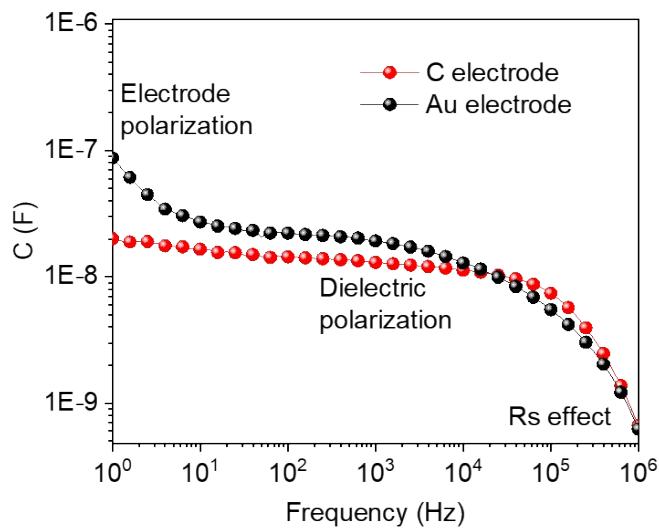
**Figure S9.** The internal quantum efficiency of champion solar cells with Au and C electrodes.  $\text{IQE} = \text{EQE}/(1-\text{R}_{\text{device}})$ , where  $\text{R}_{\text{device}}$  is the reflectance from the glass side which faces the sunlight.

**Table S6.** Parameters derived from EIS analysis of solar cells with varying top electrodes.

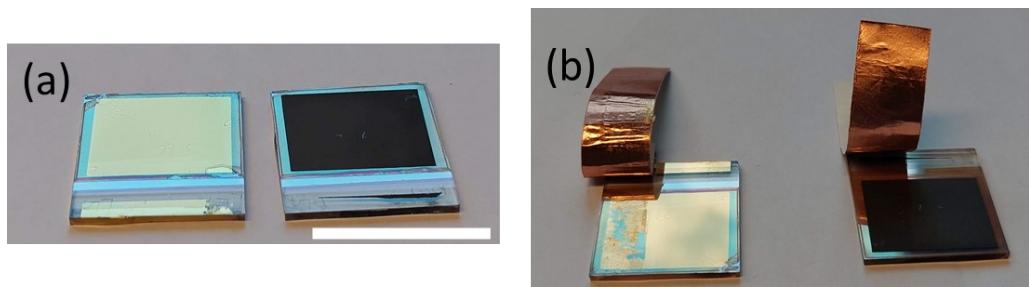
Electrode	$R_{s,\text{EIS}} [\Omega]$	$R_{\text{rec}} \text{ or } R_p [\Omega]$	CPE-T [F]	CPE-P	$V_{\text{bi}}$ [V]	Defect density [ $\text{cm}^{-3}$ ]
Carbon	198	45434	$2.52 \times 10^{-8}$	0.95	1.45	$6.75 \times 10^{17}$
Au	178	5261	$5.93 \times 10^{-8}$	0.91	1.32	$1.27 \times 10^{18}$



**Figure S10.** Mott-Schottky of FTO/TiO<sub>2</sub> thin film in 0.1 M Na<sub>2</sub>SO<sub>4</sub> at 10 kHz. Ag/AgCl was used as a reference electrode. TiO<sub>2</sub> donor concentration (N<sub>D</sub>) was calculated following previous reports.<sup>13,14</sup>



**Figure S11.** Capacitance vs. frequency curves for C and Au-based devices.



**Figure S12.** Adhesion test of Au and carbon-based devices. (a) before and (b) after peeling off with highly adhesive copper tape. Substrate size: 25 mm x 25 mm.

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